

# Reliability Test Result

Product	MOSFET	Package	SOT-89 (MPT3)
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# 1. TEST RESULT

TEST DESCRIPTION		TEST CONDITION	STANDARD	n [pcs]	Pn [pcs]
Soldering Heat Resistance	(1)	260±5°C , 10sec. , Reflow Soldering , 2 times		22	0
	(2)	260±5°C , 10sec. , Solder-Bath	JESD22-A111	22	0
	(3)	350±10°C , 3sec. , Hand Soldering		22	0
Solderability	(1)	245±5°C , 3sec. , Reflow Soldering	J-STD-002	22	0
	(2)	245±5°C , 3sec. , Solder-Bath	JESD22-B102	22	0
Thermal Shock		0°C ~ 100°C , 100cycles	-	22	0
Temperature Cycle		-55±5°C←→150±5°C , 200cycles	JESD22-A104	22	0
High Temp. High Humidity Reverse Bias		85±2°C, 85±5%RH, Specified Bias ,1000hours	JESD22-A101	22	0
Pressure Cooker Test		121±2°C , 100%RH , 203kPa , 100hours	JESD22-A102	22	0
Load Life		25°C , P <sub>D</sub> =P <sub>D</sub> max. , 1000hours	-	22	0
High Temperature Reverse Bias		Ta=Tstg max. , Specified Bias , 1000hours	JESD22-A108	22	0
High Temperature Storage		Tstg max. , 1000hours	-	22	0
Low Temperature Storage		Tstg min. , 1000hours	-	22	0
Lead strength (lead pull)		Sample body fixed, pulling lead axis direction, 5N , 10±1sec.	JEITA ED-4701/400 Test Method 401	22	0
Intermittent Operation Life		Ta=25°C±5°C , ON 130sec /OFF 230sec, Pc max., 10,000 cycles	EIAJ ED-4701/100 Test Method 106	22	0

## 2. CRITERIA

ITEM	CONDITION	CRITERIA	
Gate-Source Leakage : I <sub>GSS</sub>	Per specification	Within two times of the standard value.	
Zero Gate Voltage Drain Current : I <sub>DSS</sub>	Per specification	Within two times of the standard value.	
Forward Transfer Admittance :  Y <sub>fs</sub>	Per specification	Changing rate of ±20%	
Physical	Visual check	No outstanding change in physical.	
Coldorobility	Visual check	Reflow Soldering	Immersed surface, other than the end of pin as cut-surface, must be covered by solder.
Solderability		Solder-Bath	More than 95% of the electrode must be covered with solder.

## 3. JUDGEMENT

No failure is observed from each test item.

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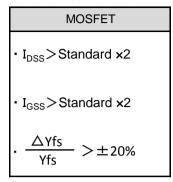
### 4.TEST DESCRIPTION

4.TEST DESCRIPTION TEST DESCRIPTION		TEST CONDITION	CRITERIA
	(1)	1) Reflow Soldering, 260±5°C(peak), 10 sec., 2 times 2) After reflow soldering, leave at room temp. for more than 2h.	Shall be no mechanical damage.  See (*1) for criteria on electrical characteristics.
1. Soldering Heat Resistance *4	(2) *3	1) Dip the leads once into solder bath til the point 1.5mm from the package body. 260±5°C, 10±1sec Solder: Sn-3Ag-0.5Cu (Lead free) 2) After dipping, leave at room temp. for more than 2h.	Shall be no mechanical damage. See (*1) for criteria on electrical characteristics.
	(3)	<ol> <li>Hand Soldering, 350±10°C , 3sec.</li> <li>After testing, leave at room temp. for more than 2h.</li> </ol>	<ul> <li>Shall be no mechanical damage.</li> <li>See (*1) for criteria on electrical characteristics.</li> </ul>
2. Solderability *5	(1)	1) Reflow Soldering, 245±5°C(peak), 3sec. Solder: Sn-3Ag-0.5Cu (Lead free)	<ul> <li>Immersed surface, other than the end of pin as cut-surface, must be covered by solder.</li> </ul>
	(2) *3	Immerse the leads into flux once til the point 1.5mm from the package body for 10s, Then into solder bath of 245±5°C til the point 1.5mm from the package body for 3±0.5s. Thereafter leave for natural dry at room temp. then wash off flux in 2-propanol.  Solder: Sn-3Ag-0.5Cu (lead free)  Flux: 2-propanol (IPA) (rosin 25wt%)	At least 95% of immersed surface, other than the end of pin as cut-surface, of must be covered by solder, which is observed through 10~20X magnifying glass.
3. Thermal Shock *6		1) Temp. & Time (Change within 10 sec,) 95~100°C (Liquid), 5min ←→ 0~5°C (Liquid), 5min 2) Freq. 100cycles. After completion of test, leave at room temp. for more than 2h.	See (*1) for criteria on electrical characteristics.
4. Temperature Cycle *6		1) Temp. &Time (Change within 5 sec.) 55°C (air), 30min ←→ 150°C (air), 30min 2) Freq. 200cycles. After completion of test, leave at room temp. for more than 2h.	See (*1) for criteria on electrical characteristics.
5. High Temp. High Humidity Reverse Bias *6		1) Ta=85±3°C, RH=75~90%, Time: 1000h 2) See (*2) for the THB bias. 3) After completion of test, leave at room temp. for more than 2h.	See (*1) for criteria on electrical characteristics.
6. Pressure Cooker Test *6		<ol> <li>Ta=121°C, 100%RH, P=203KPa [2atm]</li> <li>Time: 100h</li> <li>After completion of test, leave at room temp. for more than 2h.</li> </ol>	See (*1) for criteria on electrical characteristics.
7. Load Life *6		<ol> <li>Ta=25±5°C, P<sub>D</sub>/P<sub>D</sub>(max), Time: 1000h</li> <li>See (*2) for the THB bias.</li> <li>After completion of test, leave at room temp. for more than 2h.</li> </ol>	See (*1) for criteria on electrical characteristics.
8. High Temperature Reverse Bias *6		1) Ta=Tstg(max)±2°C, Time: 1000h 2) See (*2) for the THB bias. 3) After completion of test, leave at room temp. for more than 2h.	See (*1) for criteria on electrical characteristics.
9. High Temperature Storage		1) Ta=Tstg(max), Time: 1000h 2) After completion of test, leave at room temp. for more than 2h.	See (*1) for criteria on electrical characteristics.
10. Low Temperature Storage		1) Ta=Tstg(min), Time: 1000h 2) After completion of test, leave at room temp. for more than 2h.	See (*1) for criteria on electrical characteristics.
11. Lead Strength (Lead Pull)		The sample body is fixed, and keep pulling the lead in lead axis direction with specified load for 10±1s.	Shall be no mechanical damage, detachment, extention between the lead and the package body.
12. Intermittent Operation Life		<ol> <li>Ta=25±5°C, ON 130s/OFF 230s add Pc(max.).         Time: 10,000 cycles, See (*2) for the LL bias.</li> <li>After completion of test, leave at room temp.         for more than 2h.</li> </ol>	See (*1) for criteria on electrical characteristics.  MOS-MPT3 1

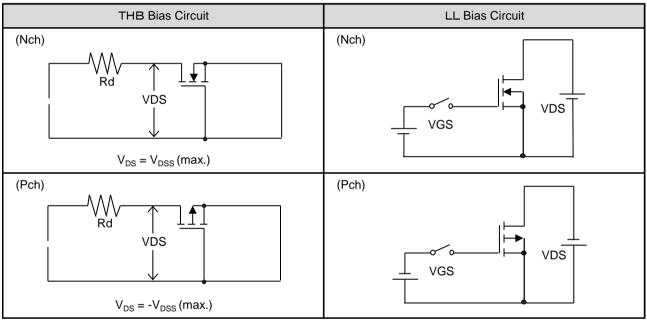
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#### **5.REMARK**

\*1 Criteria for electrical characteristics.

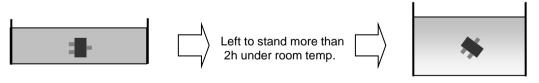


#### \*2 Bias Circuit



Bias for Power devices may be reduced as per individual specification.

#### \*3 Method of test 1, test 2



Immersed in solder bath

Wash off flux in 2-propanol

- $^*4$  Preconditioning : The test is carried out after it is left under the high temperature and the high humidity. (85  $^{\circ}$ C,85%,168h)
- \*5 Preconditioning: Aging is done with the PCT device. (105°C,100%,1.22×10<sup>5</sup>Pa,4h)
- $^{*}6$  Preconditioning : Soldering heat resistance(260  $^{\circ}$ C,10s) is carried out. (Reflow Soldering)

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